

<b>Notice of References Cited</b>	Application/Control No. 10/701,014		Applicant(s)/Patent Under Reexamination MAI, ANTHONY	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,764,928 A	08-1988	Akerberg, Dag E.	714/819
*	B	US-5,596,720 A	01-1997	Hamada et al.	709/206
*	C	US-5,701,427 A	12-1997	Lathrop, Alan	709/237
*	D	US-5,768,531 A	06-1998	Lin, Isabel Y.	709/242
*	E	US-2001/0005368 A1	06-2001	Rune, Johan	370/390
*	F	US-2001/0021188 A1	09-2001	Fujimori et al.	370/389
*	G	US-2001/0044339 A1	11-2001	Cordero et al.	463/42
*	H	US-6,349,210 B1	02-2002	Li, Chris Cho-Pin	455/450
*	I	US-2002/0035604 A1	03-2002	Cohen et al.	709/205
*	J	US-2002/0097732 A1	07-2002	Worster et al.	370/408
*	K	US-2002/0107935 A1	08-2002	Lowery et al.	709/216
*	L	US-2002/0138471 A1	09-2002	Dutta et al.	707/3
*	M	US-2002/0147810 A1	10-2002	Traversat et al.	709/224

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
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	W					
	X					

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Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

**Notice of References Cited**

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0161821 A1	10-2002	Narayan et al.	709/201
*	B	US-2002/0184310 A1	12-2002	Traversat et al.	709/204
*	C	US-2003/0097408 A1	05-2003	Kageyama et al.	709/205
*	D	US-2003/0084282 A1	05-2003	Taruguchi, Hideaki	713/155
*	E	US-2003/0126245 A1	07-2003	Feltin et al.	709/223
*	F	US-2003/0126229 A1	07-2003	Kantor et al.	709/217
*	G	US-2003/0152034 A1	08-2003	Zhang et al.	370/252
*	H	US-2003/0158961 A1	08-2003	Nomura et al.	709/237
*	I	US-2003/0177187 A1	09-2003	Levine et al.	709/205
*	J	US-2003/0217096 A1	11-2003	McKelvie et al.	709/202
*	K	US-2003/0233281 A1	12-2003	Takeuchi et al.	705/26
*	L	US-2004/0018839 A1	01-2004	Andric et al.	455/433
*	M	US-2004/0015548 A1	01-2004	Lee, Jin Woo	709/204

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

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	X					

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,701,344 B1	03-2004	Holt et al.	709/204
*	B	US-2004/0103179 A1	05-2004	Damm et al.	709/223
*	C	US-2004/0133631 A1	07-2004	Hagen et al.	709/203
*	D	US-6,807,575 B1	10-2004	Emaru et al.	709/224
*	E	US-2004/0236945 A1	11-2004	Risan et al.	713/165
*	F	US-2004/0236863 A1	11-2004	Shen et al.	709/231
*	G	US-2004/0254977 A1	12-2004	Zhang, Xiaohai	709/201
*	H	US-2004/0267876 A1	12-2004	Kakivaya et al.	709/200
*	I	US-6,829,634 B1	12-2004	Holt et al.	709/204
*	J	US-2005/0015626 A1	01-2005	Chasin, C. Scott	713/201
*	K	US-2005/0063409 A1	03-2005	Oommen, Paul	370/432
*	L	US-2005/0065632 A1	03-2005	Douglas et al.	700/200
*	M	US-2005/0080858 A1	04-2005	Pessach, Yaniv	709/206

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
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	S					
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,899,628 B2	05-2005	Leen et al.	463/42
*	B	US-6,891,801 B1	05-2005	Herzog, Christian	370/237
*	C	US-2005/0141522 A1	06-2005	Kadar et al.	370/396
*	D	US-7,017,138 B2	03-2006	Zirojevic et al.	716/16
*	E	US-7,035,911 B2	04-2006	Lowery et al.	709/217
*	F	US-7,177,950 B2	02-2007	Narayan et al.	709/248
*	G	US-2007/0237153 A1	10-2007	Slaughter et al.	370/392
*	H	US-7,533,172 B2	05-2009	Traversat et al.	709/225
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
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	V				
	W				
	X				

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